

A NOVEL FLUORESCENT AND PHOTOEMISSION APPARATUS
AND METHOD FOR SUBMICRON IC FAILURE ANALYSIS

5

ABSTRACT OF THE DISCLOSURE

A single integrated fault detection apparatus and method for
detecting heat-related and non-heat-related integrated circuit defects is
disclosed. In one embodiment, the present invention is an apparatus
comprising a first portion for detecting non-heat-related integrated circuit
10 defects. In this embodiment, the present invention further comprises a
second portion for detecting heat-related integrated circuit defects. In the
present embodiment, the second portion is integrated with the first portion
to provide a single integrated fault detection apparatus such that the heat-
related and the non-heat-related integrated circuit defects are detectable
15 using only a single integrated fault detection apparatus.

Figure 1